

Product Name: Smart Phone	Report No: ITEZA2-202400458RF7
Product Model: Note 58, Note58 Pro, Note58 Pro+, Note 59, Note59 Pro, Note59 Pro+, Note58 Plus	Security Classification: Open
Version: V1.0	Total Page: 48

TIRT Testing Report

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RF TEST REPORT

FCC ID: 2AX4YNOTE58

According to

FCC CFR Title 47 Part 2
FCC CFR Title 47 Part 22 Subpart H
FCC CFR Title 47 Part 24 Subpart E
FCC CFR Title 47 Part 27 Subpart C
FCC CFR Title 47 Part 90 Subpart S
ANSI C63.26:2015

KDB 971168 D01 Power Meas License Digital Systems v03r01

Applicant:	Shenzhen DOOGEE Hengtong Technology CO.,LTD	
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No.	
Address.	22, Longhua New District, Shenzhen, China	
Manufacturer:	Shenzhen DOOGEE Hengtong Technology CO.,LTD	
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No.	
Address.	22, Longhua New District, Shenzhen, China	
Sample No:	1000052955	
Product Name:	Smart Phone	
Brand Name:	DOOGEE	
Model No.:	Note 58, Note58 Pro, Note58 Pro+, Note 59, Note59 Pro, Note59	
Wodel No	Pro+, Note58 Plus	
Test No.:	Note 58	

Date of Receipt:	2024/11/21
Date of Test:	2024/11/21~2024/12/30
Issued Date:	2025/01/02
Testing Lab:	TIRT

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History of this test reportOriginal Report Issue Date: 2025.01.02

- No additional attachment
- o Additional attachments were issued following record

Attachment No.	Issue Date	Description



TEST SUMMARY

Test Item	Section in CFR 47	Result
DE Evenesure (CAD)	Part 1.1307	Pass*(Please refer to
RF Exposure (SAR)	Part 2.1093	SAR Report)
	Part 2.1046	
	Part 22.913(a)	
	Part 24.232(b)	
DE Output Dower	Part 27.50(b)	Pass
RF Output Power	Part 27.50(c)	FdSS
	Part 27.50(d)	
	Part 27.50(h)	
	Part 90.635	
	Part 2.1046	
Peak-To-Average Ratio	Part 22.913(d)	Pass
r eak-10-Average Natio	Part 24.232 (d)	F ass
	Part 27.50(d)	
Modulation Characteristics	Part 2.1047	N/A
	Part 2.1049	
009/ 9, 26 dB Occupied Bandwidth	Part 22.917	Pass
99% & -26 dB Occupied Bandwidth	Part 24.238	Pass
	Part 27.53(a)	
	Part 2.1051	
	Part 22.917	
	Part 24.238	
Spurious Emissions at Antenna Terminal	Part 27.53(c)(f)	Pass
opunous Emissions at Amerina Terminal	Part 27.53(g)	1 433
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
	Part 2.1053	
	Part 22.917	
	Part 24.238	
Field Strength of Spurious Radiation	Part 27.53(c)(f)	Pass
5.3 Guongar of Opariodo Nadiation	Part 27.53(g)	1 400
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	



	Part 2.1051	
	Part 22.917	
	Part 24.238	
Out of board ansiesies Board Educ	Part 27.53(c)(f)	Pass
Out of band emission, Band Edge	Part 27.53(g)	
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
	Part 2.1055(a)(1)(b)	
	Part 22.355	
Frequency stability vs. temperature	Part 24.235	Pass
	Part 27.54	
	Part 90.213	
	Part 2.1055(d)(1)(2)	
	Part 22.355	
Frequency stability vs. voltage	Part 24.235	Pass
	Part 27.54	
	Part 90.213	

Note: 1. Pass: The EUT complies with the essential requirements in the standard.

^{2.} The conclusion of this test report is judged by actual test data without considering measurement uncertainty.



2 GENERAL INFORMATION

2.1 GENERAL DESCRIPTION OF EUT

Description of Device (EUT)

EUT Name : Smart Phone

Model No. : Note 58, Note58 Pro, Note58 Pro+, Note 59, Note59 Pro, Note59 Pro+,

Note58 Plus

DIFF. : There is no difference except the name of the model. All tests are made with

the Note 58 model.

Power supply : DC 3.91V from battery or DC 5V AC Power Adapter

Support Bands : LTE Band 2/4/5/7/38//41/66

Channel Bandwidth : LTE Band 2: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz

LTE Band 4: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz

LTE Band 5: 1.4MHz, 3MHz, 5MHz, 10MHz LTE Band 7: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 38: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 41: 5MHz, 10MHz, 15MHz, 20MHz

LTE Band 66: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz

TX Frequency : LTE Band 2: 1850 ~ 1910 MHz

LTE Band 4: 1710 ~ 1755 MHz LTE Band 5: 824 ~ 849 MHz LTE Band 7: 2500 ~2570 MHz LTE Band 38: 2570 MHz ~ 2620 MHz LTE Band 41: 2535MHz ~ 2655MHz LTE Band 66: 1710 MHz ~ 1780 MHz

Modulation type : QPSK, 16QAM

Antenna Type : PIFA antenna,

LTE Band 2: Maximum Gain is -0.16dBi. LTE Band 4: Maximum Gain is -1.09dBi. LTE Band 5: Maximum Gain is -4.39dBi. LTE Band 7: Maximum Gain is 2.65Bi. LTE Band 38: Maximum Gain is 1.76dBi. LTE Band 41: Maximum Gain is 2.65dBi. LTE Band 66: Maximum Gain is -0.55dBi. Antenna information is provided by applicant.

There is WWAN diversity antenna inside the product, which is only for

receiving function.

Software version : DOOGEE-N58-EEA-Android14.0-20241106

Hardware version : SC6023U_MB_V1.0.0

Remark 1: The worst-case simultaneous transmission configuration was evaluated with no non-compliance found. Results in this report are only for 4G function, and there is no other transmitter involved.

2: The LTE Band41 upports frequency is 2535-2655MHz, Due to actual customer needs
Using software, the prototype can only operate at 2535-2655 MHZ, other frequencies have been blocked



2.2 RELATED SUBMITTAL(S) / GRANT (S)

This submittal(s) (test report) is filing to comply with Section Part 22 subpart H and Part 24 subpart E of the FCC CFR 47 Rules.

2.3 TEST FACILITY

[]	
Company:	Beijing TIRT Technology Service Co.,Ltd Shenzhen
Address:	104 Building C, Xinmingsheng Industrial Park No.132, Zhangge Old Village East Zone, Zhangge Community, Fucheng Street, Longhua District, Shenzhen, Guangdong, P. R. China
CNAS Registration Number:	CNAS L14158
A2LA Registration Number:	6049.01
FCC Accredited Lab.Designation Number:	CN1366
FCC Test Firm Registration Number:	820690
Telephone:	+86-0755-27087573

2.4 ACCESSORIES OF DEVICE (EUT)

Accessories : AC Power Adapter

Manufacturer : Shenzhen Huajin Electronics Co.,Ltd

Model : HJ-0502000-US

Ratings : Input: 100-240V~ 50/60Hz 0.3A

Output: 5.0V-2.0A 10.0W

2.5 TESTED SUPPORTING SYSTEM DETAILS

No.	Description	Manufacturer	Model	Serial Number	Certification or SDoC
1	N/A	N/A	N/A	N/A	N/A

2.6 TEST CONDITIONS

Items	Required	Actual
Temperature range:	15-35°C	24℃
Humidity range:	25-75%	56%
Pressure range:	86-106kPa	98kPa



2.7 MEASUREMENT UNCERTAINTY

Uncertainty		
Parameter	Uncertainty	
Occupied Channel Bandwidth	±142.12 KHz	
RF power conducted	±0.74 dB	
RF power radiated	±3.25dB	
Spurious emissions, conducted	±1.78dB	
Spurious emissions, radiated (9KHz~30MHz)	±2.56dB	
Spurious emissions, radiated (30MHz~1GHz)	±4.6dB	
Spurious emissions, radiated (Above 1GHz)	±4.9dB	
Conduction Emissions(150kHz~30MHz)	±3.1 dB	
Humidity	±4.6%	
Temperature	±0.7°C	
Time	±1.25%	



3 TEST INSTRUMENTS LIST

Name of Equipment	Manufacturer	Model Number	Serial Number	Last Calibration	Due Calibration
EMI Receiver	Rohde&Schwarz	ESIB 40	YH-TIRT-SAC-966 -20220911	2024/01/05	2025/01/04
Integral Antenna	Schwarzbeck	VULB 9163	01314	2023/12/11	2025/12/10
Integral Antenna	Rohde&Schwarz	HF907	RSM2991424	2023/12/11	2025/12/10
Preamplifier	Emtrace	RP01A	'02017	2024/01/05	2025/01/04
Preamplifier	Schwarzbeck	BBV9744	00143	2024/01/05	2025/01/04
Loop Antenna	ZHINAN	ZN30900A	12024	2024/01/05	2025/01/04
Exposure Level Tester	narda	ELT-400	N-0925	2024/01/05	2025/01/04
Horn Antenna	Schwarzbeck	BBHA9170	00956	2024/01/05	2025/01/04
RF Cable	/	LMR400UF-NMNM-7. 0M	/	2024/01/05	2025/01/04
RF Cable	/	SFT2050PUR-NMNM -7.0M	/	2024/01/05	2025/01/04
EMI Receiver	Rohde&Schwarz	ESR7	1316.3003K07-10 2611-mk	2024/11/02	2025/11/01
LISN	Rohde&Schwarz	ENV216	3560.655.12-1029 15-Bp	2024/11/02	2025/11/01
ISN	Schwarzbeck	ENY81	1309.8510.03	2024/01/05	2025/01/04
ISN	Schwarzbeck	ENY81-CAT6	1309.8526.03-101 976-kh	2024/01/05	2025/01/04
RF Cable	\	SFT2050PUR-NMNM -2.0M	\	2024/01/05	2025/01/04
CMW500	ROHDE&SCHWARZ	CMW500	120434	2024/01/05	2025/01/04
Spectrum analyzer	ROHDE&SCHWARZ	FSU26	200732	2024/01/05	2025/01/04
Spectrum analyzer	ROHDE&SCHWARZ	FSV40-N	101722	2024/01/05	2025/01/04
vector Signal Generator	KEYSIGHT	N5182B	MY56200458	2024/01/05	2025/01/04
vector Signal Generator	HEWLETT PACKARD	83752A	3610A02458	2024/01/05	2025/01/04
Filter	HEWLETT PACKARD	JS0806-F	19K8060209	2024/01/05	2025/01/04
Wireless comprehensive tester	ANRISTU	MT8821C	SN6262170409	2024/01/05	2025/01/04
Wireless comprehensive tester	ANRISTU	MT8000A	SN6262166782	2024/01/05	2025/01/04



Report No.:ITEZA2-202400458RF7

	Hubei world for				
ROB ANT	communication Co.,	SW-700/2700XP-4	/	/	/
	LTD				

4 SYSTEM TEST CONFIGURATION

4.1 TEST MODE

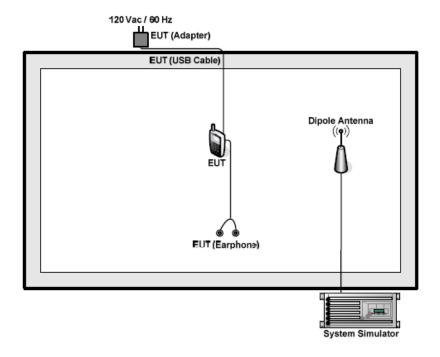
During all testing, EUT is in link mode with base station emulator at maximum power level. The spurious emission measurements were carried out in semi-anechoic chamber with 3-meter test range, and EUT is rotated on three test planes to find out the worst emission.

Test modes					
Band	Radiated	Conducted			
LTE Band 2	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link			
LTE Band 4	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link			
LTE Band 5	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link			
LTE Band 7	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link			
LTE Band 38	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link			
LTE Band 41	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link			
LTE Band 66	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link			

Note: Antenna port conducted and radiated test items were performed according to KDB 971168 D01 Power Meas License Digital Systems v03r1 with maximum output power.

Radiated measurements were performed with rotating EUT in different three orthogonal test planes to find the maximum emission.

4.2 CONFIGURATION OF TESTED SYSTEM





4.3 CONDUCTED OUTPUT POWER Test Requirement: Part 2.1046, Part 22.913(a), Part 24.232(c), Part 27.50(b), Part 27.50(c), Part 27.50(d), Part 27.50(h), Part 90.635 Test Method: ANSI C63.26:2015 Limit: LTE Band 2: 2W LTE Band 4: 1W LTE Band 5: 7W

LTE Band 7: 2W

LTE Band 38: 2W LTE Band 41: 2W LTE Band 66: 1W

Test setup:

EUT Splitter Communication
Tester

Power meter

Note: Measurement setup for testing on Antenna connector

Test Procedure:

- 1. The transmitter output port was connected to base station.
- The RF output of EUT was connected to the power meter by RF cable and attenuator, the path loss was compensated to the results for each measurement.
- 3. Set EUT at maximum power through base station.
- 4. Select lowest, middle, and highest channels for each band and different modulation.
- Measure the maximum burst average power.

Test Instruments:	Refer to section 3 for details
Test mode:	Refer to section 4.1 for details
Test results:	Pass

Note: Please refer to Appendix A of the Appendix Test Data.



4.4 PEAK-TO-AVER	AGE RATIO
Test Requirement:	Part 22.913(d), FCC part24.232(d) and FCC part27.50(d)(5)
Test Method:	ANSI C63.26:2015
Test Limit:	Used complementary cumulative distribution function (CCDF) of analyzer to determine that PAPR will not exceed 13 dB for more than 0.1 percent of the time
Test setup:	SPA SPA SPA Note: Measurement setup for testing on Antenna connector
Test Procedure:	 The testing follows FCC KDB 971168 D01 v03r01 Section 5.7 The EUT was connected to spectrum and system simulator via a power divider Using the CCDF measurement ofspectrum analyzer; Set RBW≥OBW or specified reference bandwidth; Set the number of counts to a value that stabilizes the measured CCDF curve; Set the measurement interval as 1ms Record the maximum PAPR level associated with a probability of 0.1%.
Test Instruments:	Refer to section 3 for details
Test mode:	Refer to section 4.1 for details
Test results:	Pass

Note: Please refer to Appendix B of the Appendix Test Data.



OCCUPY BANDWIDTH FCC part22.913(a), FCC part24.232(b) and FCC part27.53(a), FCC part Test Requirement: ANSI C63.26:2015 Test Method: Test setup: Communication EUT Splitter Tester SPA Note: Measurement setup for testing on Antenna connector 1.The EUT's output RF connector was connected with a short cable to Test Procedure: the spectrum analyzer, set center frequency to channel center frequency. 2.RBW was set to about 1%-5% of emission OBW, VBW≥ 3 X RBW. 3.Set spectrum analyzer detection mode to peak, and the trace mode to max hold. 4. Use the 99% OBW function, The 99% power OBW can be found on the plot, determine the "-26dB amplitude" as equal to reference value -26dB. Refer to section 3 for details Test Instruments: Refer to section 4.1 for details Test mode: Pass Test results:

Note: Please refer to Appendix C of the Appendix Test Data.



MODULATION CHARACTERISTIC According to FCC § 2.1047(d), Part 24E & Part 27 there is no specific requirement for digital modulation, therefore modulation characteristic is not presented.



OUT OF BAND EMISSION AT ANTENNA TERMINALS Part 2.1051 Test Requirement: Part 22.917 Part 24.238 Part 27.53(c)(f) Part 27.53(g) Part 27.53(h) Part 27.53(m) Part 90.691 Test Method: ANSI C63.26:2015 ≤ -13dBm(LTE Band5) Limit: ≤ -13dBm(LTE Band2) ≤ -13dBm(LTE Band4,66) ≤ -25dBm(LTE Band 7, 38, 41) Test setup: Communication Splitter EUT Tester Filter SPA Note: Measurement setup for testing on Antenna connector Test Procedure: The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 1MHz, sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. 3 For the out of band: Set the RBW=1MHz, VBW = 3MHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions. Refer to section 3 for details Test Instruments: Refer to section 4.1 for details Test mode: **Pass** Test results:

Note: Please refer to Appendix D of the Appendix Test Data.



ERP, EIRP MEASUREMENT Part 2.1046, Part 22.913(a), Part 24.232(b), Part 27.50(b), Part Test Requirement: 27.50(c), Part 27.50(d), Part 27.50(h), Part 90.635 Test Method: ANSI C63.26:2015 ERP≤ 7W(38.45dBm) (LTE Band 5) Limit: EIRP≤ 2W(33.00dBm) (LTE Band 2) EIRP≤ 1W(30.00dBm) (LTE Band 4,66) EIRP≤ 2W(33.00dBm) (LTE Band 7,38,41) Test setup: Below 1GHz Antenna Tower Search Antenna EUT RF Test Turn Ground Plane Above 1GHz Horn Antenna EUT Spectrum Analyzer Amplifier Substituted method: Antenna mast Ground plane d: distance in meters 1-4 meter d:3 meter S.G. SPA Substituted Dipole or Horn Antenna Bi-Log Antenna or Horn Antenna



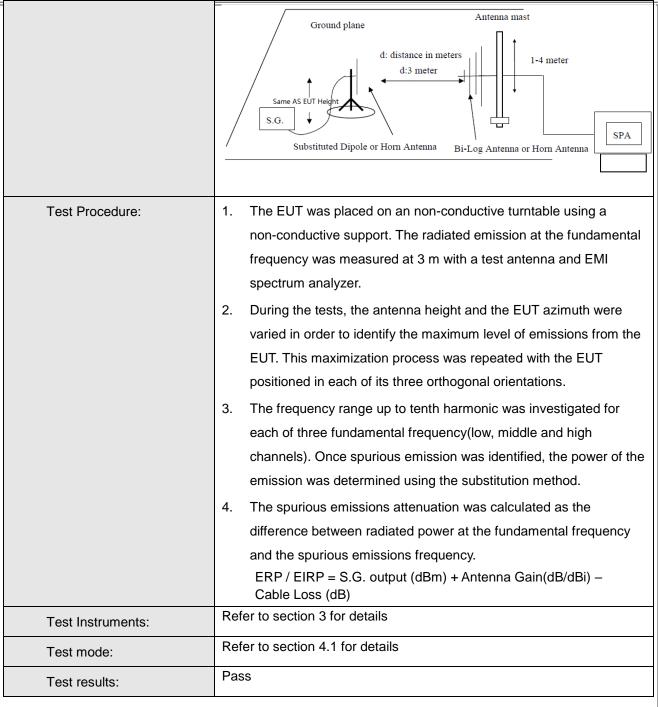
Test Procedure:	The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI
	spectrum analyzer.
	2. During the measurement, the EUT was communication with the
	station. The highest emission was recorded with the rotation of the
	turntable and the lowering of the test antenna from 4m to 1m. The
	reading was recorded and the field strength (E in dBuV/m) was
	calculated.
	3. ERP were measured using a substitution method. The EUT was
	replaced by dipole antenna connected, the S.G. output was
	recorded and ERP was calculated asfollows:
	ERP = S.G. output (dBm) + Antenna Gain (dBd) - Cable Loss (dB)
	4. EIRP were measured using a substitution method. The EUTwas
	replaced by or horn antenna connected, the S.G. output was
	recorded and EIRP was calculated asfollows:
	EIRP = S.G. output (dBm) + Antenna Gain (dBi) – Cable Loss (dB)
Test Instruments:	Refer to section 3 for details
Test mode:	Refer to section 4.1 for details
Test results:	Pass
Remark:	H,E1,E2 mean for EUT polarization of X, Y, Z

Note: Please refer to Appendix A of the Appendix Test Data.



FIELD STRENGTH OF SPURIOUS RADIATION MEASUREMENT Part 2.1053 Test Requirement: Part 22.917 Part 24.238 Part 27.53(c)(f) Part 27.53(g) Part 27.53(h) Part 27.53(m) Part 90.691 Test Method: ANSI C63.26:2015 Limit: ≤ -13dBm(LTE Band 5) ≤ -13dBm(LTE Band 2) ≤ -13dBm(LTE Band 4,66) ≤ -25dBm(LTE Band 7, 38, 41) Test setup: Below 1GHz Antenna Tower Search RF Test Turn Ground Plane Above 1GHz Antenna Tower Horn Antenna EUT Spectrum Analyzer Turn Amplifier Substituted method:







Measurement Data:

QPSK Mode:

QPSK Mode:	I TE D	10/4 48411-1	To at all annual	1
Test mode:		2(1.4MHz)	Test channel:	Lowest
Frequency (MHz)	Spurious Polarization	Level (dBm)	Limit (dBm)	Result
3732.07	Vertical	-31.36		
5599.26	Vertical	-31.30	-	
7430.50	V	-30.77	-13.00	Pass
9285.16	V	-42.41	-13.00	Fa55
11257.47	V	-42.41	-	
3732.36	v Horizontal	-32.76		
5525.52	H	-31.91	-	
7406.36		-37.26	12.00	Pass
		+	-13.00	Pass
9246.19	H	-41.67	_	
11234.31	H LTE Day		Took also mode	88: 441.
Test mode:		2(1.4MHz)	Test channel:	Middle
Frequency (MHz)	Polarization	Emission	Limit (dBm)	Result
3732.20	Vertical	Level (dBm) -30.92		
5641.56	Vertical	-31.01	-	
7508.39	V	-32.59	-13.00	Pass
9485.24	V	-43.67	-13.00	
11408.72	V	-45.07	-	
3717.51	Horizontal	-32.83		
5673.85	Н	-31.56	-	
7531.93	H	-39.59	-13.00	Pass
9427.04	H	-38.47		
11329.94	Н			
Test mode:		2(1.4MHz)	Test channel:	Highest
- (111)		Emission		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3833.08	Vertical	-30.79		
5744.44	V	-31.73]	
7649.44	V	-33.76	-13.00	Pass
9521.48	V	-43.54]	
11607.53	V]	
3834.24	Horizontal	-32.09		
5747.39	Н	-31.72]	
7625.62	Н	-38.26	-13.00	Pass
9578.78	Н	-40.99		
11532.52	Н]	

- 1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	4(1.4MHz)	Test channel:	Lowest
Fragues (MIII-)	Spurious	Emission	Lineit (dDne)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
3428.73	Vertical	-32.02		
5146.07	V	-28.37		
6871.77	V	-33.00	-13.00	Pass
8541.67	V	-45.09		
10329.75	V			
3429.69	Horizontal	-31.55		
5131.61	Н	-39.15		
6870.05	Н	-36.68	-13.00	Pass
8605.62	Н	-34.96		
10244.71	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
r requericy (Miriz)	Polarization	Level (dBm)	Limit (dbin)	Nesuit
3442.50	Vertical	-31.50		
5142.06	V	-30.63		Pass
6979.81	V	-34.66	-13.00	
8667.77	V	-44.25		
10476.17	V			
3472.40	Horizontal	-32.55		Pass
5119.29	Н	-38.22		
6965.47	Н	-36.98	-13.00	
8716.45	Н	-35.47		
10320.21	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Highest
Frequency (MHz)		Emission	Limit (dBm)	Result
	Polarization	Level (dBm)	Limit (dDim)	result
3515.51	Vertical	-31.17		
5223.50	V	-28.70		
7032.63	V	-31.27	-13.00	Pass
8771.24	V	-43.75		
10667.08	V			
3545.29	Horizontal	-32.46		
5252.27	Н	-38.07		
7060.22	Н	-36.93	-13.00	Pass
8822.85	Н	-36.71]	
10547.02	Н			

- 1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	5(1.4MHz)	Test channel:	Lowest	
Fragues av (MHz)	Spurious	Emission	Limit (dDm)	Dooult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1615.14	Vertical	-32.47			
2445.81	V	-32.45			
3224.50	V	-33.00	-13.00	Pass	
4144.32	V	-44.21			
5073.82	V				
1812.60	Horizontal	-31.00			
2505.05	Н	-39.67			
3885.90	Н	-35.33	-13.00	Pass	
4312.21	Н	-33.27			
5147.99	Н				
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Middle	
Frequency (MHz)	Spurious	Emission	Limit (dPm)	Result	
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dBm)	Result	
1638.54	Vertical	-31.63			
2422.86	V	-29.29		Pass	
3252.25	V	-32.73	-13.00		
4287.77	V	-44.43			
5159.87	V				
4750.81	Horizontal	-31.12			
2667.34	Н	-38.56			
3856.74	Н	-36.45	-13.00	Pass	
4425.62	Н	-35.48			
5148.33	Н				
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Highest	
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
1 requeries (IVII 12)	Polarization	Level (dBm)	Limit (dDin)	rtesuit	
1703.51	Vertical	-34.48			
2561.92	V	-33.12			
3420.25	V	-31.82	-13.00	Pass	
4370.70	V	-43.92			
5260.22	V				
1751.79	Horizontal	-31.84			
2876.73	Н	-39.22	_		
3441.25	Н	-37.21	-13.00	Pass	
4394.88	Н	-36.67	_		
5147.90	Н				

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- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	d 7(5MHz)	Test channel:	Lowest	
Fragueray (MIII-)	Spurious	Emission	Lineit (dDne)	Decult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
5229.11	Vertical	-31.02			
4861.83	V	-29.13			
10094.91	V	-32.59	-25.00	Pass	
13594.93	V	-44.35			
15234.46	V				
5139.40	Horizontal	-31.59			
7945.88	Н	-38.61			
10156.13	Н	-35.31	-25.00	Pass	
12812.71	Н	-35.97			
15137.93	Н				
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Middle	
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
Frequency (IVIF12)	Polarization	Level (dBm)	Limit (dbin)	Result	
5158.12	Vertical	-30.23			
7640.84	V	-30.95			
10225.45	V	-31.18	-25.00	Pass	
13285.35	V	-44.00			
15637.14	V				
5131.37	Horizontal	-33.84			
7739.37	Н	-38.73			
10278.97	Н	-35.65	-25.00	Pass	
13878.45	Н	-33.78			
15364.08	Н				
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Highest	
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
1 requeries (IVII 12)	Polarization	Level (dBm)	Limit (dbin)	resuit	
5240.33	Vertical	-33.61			
7884.18	V	-34.55			
10349.04	V	-31.34	-25.00	Pass	
12925.07	V	-44.78			
15441.79	V				
5226.78	Horizontal	-32.00			
7738.97	Н	-38.27			
10357.97	Н	-36.54	-25.00	Pass	
12778.99	Н	-36.32			
15364.35	Н				

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Test mode	LTE I	Band 38(5MHz)	Test channel:	Lowest
Frequency (MHz)	Spu	rious Emission	Limit (dDm)	Result
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dBm)	Result
2628.95	Vertical	-31.21		
5256.32	V	-31.73		
10564.81	V	-30.44	-25.00	Pass
12217.19	V	-43.90		
13697.89	V			
2643.55	Horizontal	-33.33		
5233.23	Н	-38.77		
10852.86	Н	-37.60	-25.00	Pass
12304.40	Н	-37.06		
13264.22	Н			
Test mode	LTE I	Band 38(5MHz)	Test channel:	Middle
Fraguency (MUz)	Spu	rious Emission	Limit (dPm)	Dogult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2758.63	Vertical	-29.15		
5484.60	V	-33.04		Pass
10639.65	V	-31.03	-25.00	
12867.45	V	-45.86		
15710.35	V			
2687.70	Horizontal	-33.33		
5437.26	Н	-37.39		
10840.83	Н	-37.07	-25.00	Pass
12310.16	Н	-35.67		
15331.05	Н			
Test mode	LTE I	Band 38(5MHz)	Test channel:	Highest
[Spu	rious Emission	Lineit (ADne)	Danult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2627.13	Vertical	-30.63		
6894.74	V	-32.98		
10440.11	V	-30.54	-25.00	Pass
12726.85	V	-43.58		
15637.80	V			
2690.03	Horizontal	-28.49	-25.00	
5192.20	Н	-37.12		
10761.53	Н	-36.76		Pass
13307.59	Н	-36.91		
16260.18	Н			

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- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode	LTE	Band 41(5MHz)	Test channel:	Lowest
Fraguenov (MUz)	Spi	Spurious Emission		Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3676.00	Vertical	-28.33		
8634.37	V	-33.20		
10232.34	V	-33.53	-25.00	Pass
12662.96	V	-43.41		
13375.30	V			
3992.04	Horizontal	-32.10		
9810.97	Н	-38.74		
10273.44	Н	-37.36	-25.00	Pass
12317.68	Н	-34.57		
13164.11	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Middle
[/ NALL	Spi	urious Emission	Limit (-IDms)	Danult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3578.10	Vertical	-31.73		
5976.30	V	-32.52		
8944.35	V	-33.05	-25.00	Pass
10238.98	V	-43.49		
13803.07	V			
5870.03	Horizontal	-29.58		
7236.24	Н	-40.76		
10342.31	Н	-34.65	-25.00	Pass
12305.72	Н	-26.92		
13262.51	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Highest
	Spi	urious Emission	Limit (-IDms)	Danult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3115.90	Vertical	-33.14		
5637.01	V	-33.03		
8943.37	V	-33.60	-25.00	Pass
10362.44	V	-44.03		
12876.24	V			
5132.20	Horizontal	-33.17		
8676.23	Н	-38.87		
10303.38	Н	-35.60	-25.00	Pass
12710.33	Н	-36.29		
13592.05	Н		-	

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- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	66(1.4MHz)	Test channel:	Lowest
Frequency		Emission		
(MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3316.41	Vertical	-31.45		
5688.87	V	-32.96		Pass
7306.47	V	-32.42	-13.00	
8299.82	V	-44.16		
10441.84	V			
3335.15	Horizontal	-32.81		
5230.93	Н	-38.68		
6951.31	Н	-37.64	-13.00	Pass
8917.15	Н	-37.25		
10269.68	Н			
Test mode:	LTE Band	66(1.4MHz)	Test channel:	Middle
Frequency	Spurious	Emission	Limit (dDm)	Dooult
(MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2887.29	Vertical	-35.41		
5371.47	V	-34.89		Pass
7517.70	V	-34.67	-13.00	
9867.37	V	-44.62		
10368.76	V			
3021.80	Horizontal	-32.80		
5236.42	Н	-38.14		Pass
7652.52	Н	-36.99	-13.00	
8886.20	Н	-35.57		
10400.84	Н			
Test mode:	LTE Band	66(1.4MHz)	Test channel:	Highest
Frequency	Spurious	Emission	Limit (dPm)	Result
(MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3749.48	Vertical	-35.34		
5314.98	V	-34.43		
7235.06	V	-35.53	-13.00	Pass
8632.50	V	-44.58		
10575.52	V			
3335.50	Horizontal	-32.89		
5292.80	Н	-38.64	-13.00	
7329.02	Н	-36.52		Pass
8879.80	Н	-35.35		
10128.27	Н			

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The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst



Test mode:	LTE Band	2 (1.4MHz)	Test channel:	Lowest
Crossianos (MIII-)	Spurious	Emission	Limait (alDina)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
3533.25	Vertical	-33.17		
5714.53	V	-39.42		
8612.65	V	-32.18	-13.00	Pass
9731.98	V	-45.82		
11405.01	V			
3651.78	Horizontal	-32.77		
5558.83	Н	-35.60		
7725.87	Н	-40.87	-13.00	Pass
9384.72	Н	-39.36		
12395.62	Н			
Test mode:	LTE Band	2 (1.4MHz)	Test channel:	Middle
Fire (MILL)	Spurious	Emission	1.1 m.1(/ ID m.)	D II
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3870.59	Vertical	-33.01		
5851.20	V	-39.77		Pass
7913.87	V	-31.43	-13.00	
9391.16	V	-45.77		
12165.08	V			
3355.20	Horizontal	-36.48		Pass
5547.08	Н	-37.68		
7958.82	Н	-40.46	-13.00	
9908.91	Н	-40.56		
11344.04	Н			
Test mode:	LTE Band	2 (1.4MHz)	Test channel:	Highest
Fraguenov (MHz)	Spurious	Emission	Limit (dDm)	Dogult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2898.42	Vertical	-33.72		
5651.60	V	-42.25		
7842.80	V	-34.15	-13.00	Pass
9309.56	V	-41.85		
12193.85	V			
3790.85	Horizontal	-36.31	-13.00	
5667.74	Н	-37.29		
7558.70	Н	-40.36		Pass
9503.24	Н	-39.21		
11487.25	Н			

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Test mode:	LTE Band	4(1.4MHz)	Test channel:	Lowest
F (MIL)	Spurious	Emission	Limit (dDm)	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3417.02	Vertical	-33.06		Pass
5274.34	V	-40.25		
6305.54	V	-29.53	-13.00	
8715.87	V	-48.41		
11295.10	V		7	
3353.11	Horizontal	-34.50		
4932.67	Н	-36.50	7	
7716.59	Н	-40.58	-13.00	Pass
9647.89	Н	-40.27		
10417.56	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Middle
Fragueney (MHz)	Spurious	Emission	Limit (dDm)	Dooult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3291.05	Vertical	-37.32		
5275.55	V	-39.73		Pass
7310.70	V	-33.54	-13.00	
8993.91	V	-46.17	7	
10296.80	V			
3385.76	Horizontal	-36.94		Pass
5227.22	Н	-35.23		
6896.31	Н	-41.04	-13.00	
9344.85	Н	-37.57		
10457.30	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requerity (Wir 12)	Polarization	Level (dBm)	Limit (abin)	Nesuit
3236.36	Vertical	-34.85		
5145.73	V	-41.80		
8613.61	V	-30.73	-13.00	Pass
9570.00	V	-48.27		
11306.96	V			
3539.62	Horizontal	-35.17	-13.00 Pass	
5338.21	Н	-37.10		
7284.31	Н	-40.25		Pass
8952.85	Н	-37.47		
10360.50	Н			

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Test mode:	LTE Band	5(1.4MHz)	Test channel:	Lowest
Fragues of (MIII-)	Spurious	Emission	Limit (dPm) Posult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1964.94	Vertical	-36.21		Pass
2537.00	V	-40.97		
3628.45	V	-36.10	-13.00	
4267.35	V	-45.93		
5679.48	V			
1676.32	Horizontal	-35.16		
2443.22	Н	-37.29		
3326.86	Н	-40.14	-13.00	Pass
4268.25	Н	-40.14		
5080.68	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Middle
Fraguency (MHz)	Spurious	Emission	Limit (dDm)	Dooult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1684.50	Vertical	-35.59		
2532.37	V	-38.74		Pass
3440.14	V	-35.74	-13.00	
4231.92	V	-46.51		
5164.42	V			
1589.07	Horizontal	-36.71		Pass
2281.79	Н	-38.55		
3483.72	Н	-41.44	-13.00	
4199.53	Н	-42.02		
5560.56	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requeries (Wir 12)	Polarization	Level (dBm)	Limit (dDin)	resuit
1171.25	Vertical	-36.94		
2379.50	V	-36.56	_	
3213.96	V	-30.68	-13.00	Pass
4258.27	V	-44.98		
5166.50	V			
1701.90	Horizontal	-31.99	-13.00 Pass	
2513.50	Н	-29.71		
3425.72	Н	-39.18		Pass
4259.41	Н	-36.99		
5121.88	Н			

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Test mode:	LTE Band	d 7(5MHz)	Test channel:	Lowest
_		Emission		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5151.69	Vertical	-31.26		Pass
7373.93	V	-39.68		
9047.26	V	-32.05	-25.00	
12423.17	V	-44.77		
15424.27	V			
5177.56	Horizontal	-30.87		
7322.58	Н	-35.67		
9683.58	Н	-38.34	-25.00	Pass
12497.48	Н	-39.89	7	
15325.55	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Middle
Eroguanov (MHz)	Spurious	Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5151.47	Vertical	-31.61		
7734.08	V	-38.41		Pass
10134.26	V	-36.32	-25.00	
12717.14	V	-46.86		
15293.58	V			
5179.81	Horizontal	-36.65		Pass
7621.09	Н	-38.99		
10311.80	Н	-38.36	-25.00	
12357.05	Н	-38.36		
15385.08	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Highest
Frequency (MHz)		Emission	Limit (dBm)	Result
	Polarization	Level (dBm)	Limit (dBin)	result
5054.60	Vertical	-34.24		
7884.23	V	-39.49		Pass
10321.35	V	-30.14	-25.00	
13020.40	V	-44.69		
15697.01	V			
5181.12	Horizontal	-31.25	-25.00 Pass	
7827.22	Н	-36.29		
10253.42	Н	-41.27		Pass
12904.12	Н	-41.06		
15557.99	Н			

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Test mode	LTE	Band 38(5MHz)	Test channel:	Lowest
Fragues av (MILI-)	Sp	urious Emission	Lineit (dDree)	Desuit
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2390.88	Vertical	-32.78		
5321.61	V	-41.35		
10254.83	V	-34.66	-25.00	Pass
12951.17	V	-46.09		
13548.72	V			
3153.69	Horizontal	-35.42		
5270.56	Н	-38.60		
10080.23	Н	-37.88	-25.00	Pass
12799.55	Н	-41.91		
13083.57	Н			
Test mode	LTE	Band 38(5MHz)	Test channel:	Middle
Fraguenov (MHz)	Sp	urious Emission	Limit (dDm)	Dooult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2612.98	Vertical	-33.50		
5319.68	V	-39.71		Pass
10580.43	V	-31.82	-25.00	
12815.12	V	-45.14		
15697.22	V			
2619.73	Horizontal	-31.71		Pass
5241.71	Н	-36.76		
10913.43	Н	-39.38	-25.00	
12410.77	Н	-42.09		
15513.80	Н			
Test mode	LTE	Band 38(5MHz)	Test channel:	Highest
Fraguenov (MHz)	Sp	urious Emission	Limit (dDm)	Dooult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2605.71	Vertical	-34.77		
5804.08	V	-40.45		
10663.17	V	-34.01	-25.00	Pass
12740.03	V	-46.46		
16344.41	V			
2681.64	Horizontal	-36.15		
5495.71	Н	-37.96	-25.00 Pa	
10327.97	Н	-40.73		Pass
13038.70	Н	-38.72		
16437.84	Н			

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Test mode	LTE	Band 41(5MHz)	Test channel:	Lowest
Fraguenov (MHz)	Sp	urious Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	rtesuit
4863.00	Vertical	-34.49		
9976.26	V	-38.60		Pass
10259.97	V	-30.55	-25.00	
12345.36	V	-46.24		
13093.76	V			
4960.29	Horizontal	-33.21		
9904.72	Н	-39.82		
10152.42	Н	-37.31	-25.00	Pass
12609.50	Н	-38.76		
13274.73	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Middle
Fraguenov (MHz)	Sp	urious Emission	Limit (dDm)	Dogult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5100.75	Vertical	-34.65		
10055.57	V	-39.85	-25.00	Pass
12224.68	V	-32.50		
13515.86	V	-43.81		
15383.91	V			
5090.20	Horizontal	-34.26		
10118.13	Н	-36.15		Pass
12510.38	Н	-39.52	-25.00	
13294.64	Н	-37.80		
15528.01	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Highest
Frequency (MHz)	Sp	urious Emission	Limit (dDm)	Result
riequency (Minz)	Polarization	Level (dBm)	Limit (dBm)	Result
5151.71	Vertical	-34.77		
10192.02	V	-39.84		
12129.33	V	-28.85	-25.00	Pass
13298.85	V	-44.33		
15323.41	V			
5066.07	Horizontal	-34.50		
10320.12	Н	-37.34		
12803.57	Н	-38.70	-25.00 Pas	Pass
13634.69	Н	-38.65		
15311.04	Н			

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Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Lowest
		Emission		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3440.17	Vertical	-32.06		
5281.68	V	-39.67		Pass
6711.49	V	-30.15	-13.00	
8386.24	V	-45.49		
10287.25	V			
3464.06	Horizontal	-34.16		
5199.44	Н	-35.85		
6910.09	Н	-38.27	-13.00	Pass
8577.19	Н	-39.19		
10329.51	Н			
Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (Wir 12)	Polarization	Level (dBm)	Limit (dDin)	Nesuit
3461.16	Vertical	-34.48		Pass
5171.22	V	-38.51		
6947.49	V	-33.67	-13.00	
8782.56	V	-43.88		
10418.52	V			
3381.83	Horizontal	-33.57		
5253.13	Н	-36.76		
6994.06	Н	-38.21	-13.00	Pass
8745.39	Н	-38.51		
10641.32	H			
Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Highest
Frequency (MHz)	•	Emission	Limit (dBm)	Result
	Polarization	Level (dBm)	2 (d.2)	rtooan
3355.29	Vertical	-31.61		
5169.03	V	-33.31		
7044.95	V	-29.36	-13.00	Pass
8759.69	V	-45.75		
10599.71	V			
3584.22	Horizontal	-34.30	-13.00 Pass	
5266.29	Н	-32.82		
7083.66	Н	-39.17		Pass
8834.37	Н	-39.33		
10584.11	Н			

- 1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test Requirement:	t Requirement: Part 2.1055(a)(1)(b), Part 22.355	
	Part 24.235 , Part 27.54, Part 90.213	
Test Method:	ANSI C63.26:2015	
Limit:	2.5ppm(Part 22)	
	Within the authorized bands of operation(Part 24, Part 27)	
Test setup:	Temperature Chamber	
	Spectrum analyzer EUT Att.	
	Variable Power Supply	
	Note: Measurement setup for testing on Antenna connector	
Test procedure:	 The equipment under test was connected to an external DC pow supply and input rated voltage. RF output was connected to a frequency counter or spectru analyzer via feed through attenuators. The EUT was placed inside the temperature chamber. 	
	 Set the spectrum analyzer RBW low enough to obtain the desir frequency resolution and measure EUT 25°C operating frequency as reference frequency. Turn EUT off and set the chamber temperature to -20°C. After the temperature stabilized for approximately 30 minutes recorded to the chamber temperature. 	
	frequency. 6. Repeat step measure with 10°C increased per stage until this highest temperature of +50°C reached.	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	
Remark:	If all frequencies stability are comply with the lower limit, then all resucan be considered qualified	



4.11 FREQUENCY STABILITY V.S. VOLTAGE MEASUREMENT Part 2.1055(d)(1)(2) Test Requirement: Part 22.355 Part 24.235 Part 27.54 Part 90.213 Test Method: ANSI C63.26:2015 2.5ppm Limit: Band II & Band VII should be within authorized band. Test setup: Temperature Chamber EUT Spectrum analyzer Att. Variable Power Supply Note: Measurement setup for testing on Antenna connector Set chamber temperature to 20°C. Use a variable DC power source Test procedure: to power the EUT and set the voltage to rated voltage. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency. Reduce the input voltage to specified extreme voltage variation (+/-15%) and endpoint, record the maximum frequency change. Refer to section 3 for details Test Instruments: Refer to section 4.1 for details Test mode: **Pass** Test results:

Note: Please refer to Appendix Fof the Appendix Test Data.

Remark:

3.61VDC, max voltage is 4.18VDC.

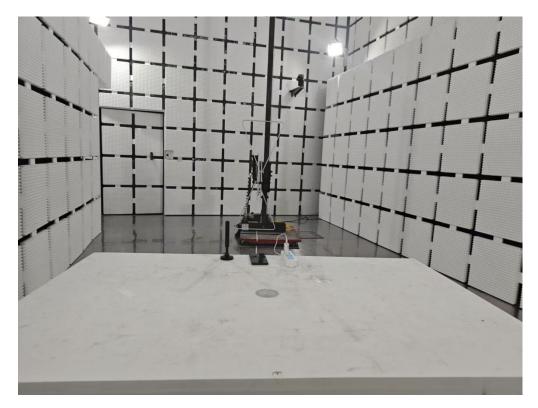
results can be considered qualified

1. Manufacturer specified the battery operating end point voltage is

2. If all frequencies stability are comply with the lower limit, then all



4.12 TEST SETUP PHOTO







4.13 PHOTOS OF EUT



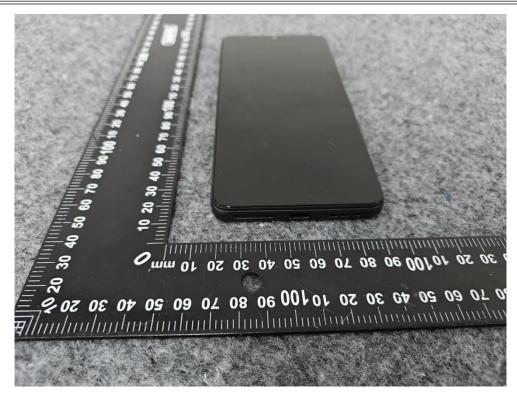






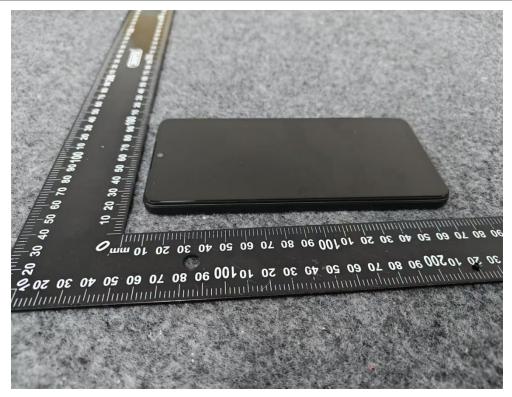






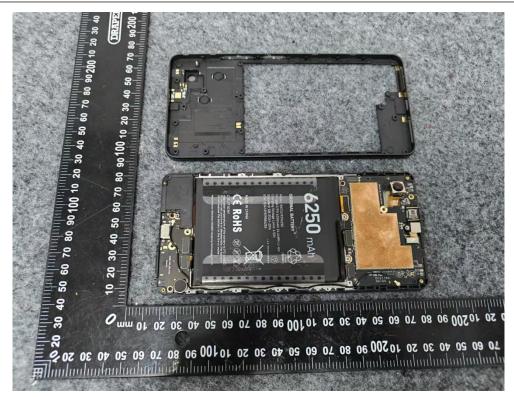


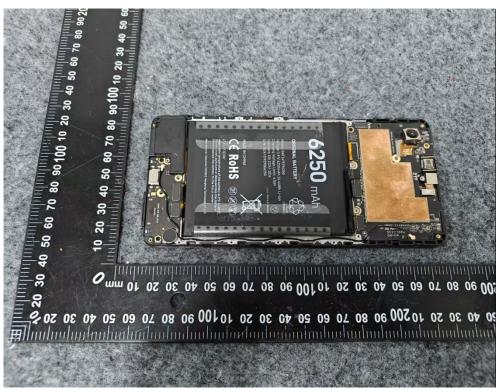




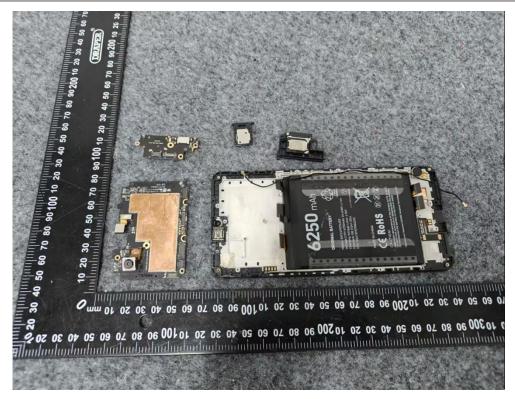


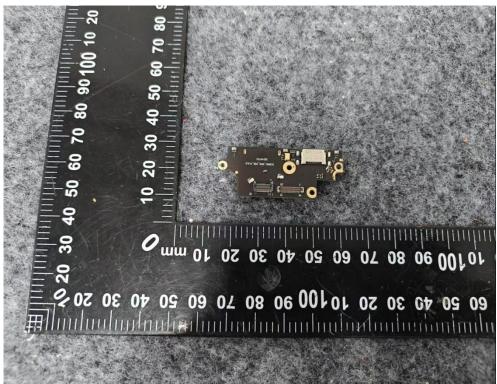




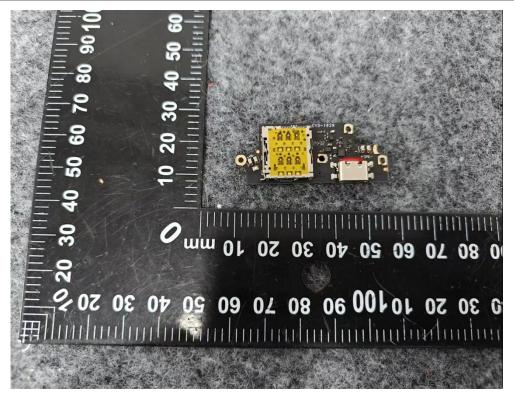


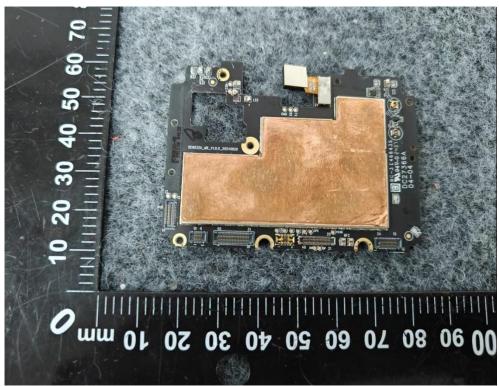




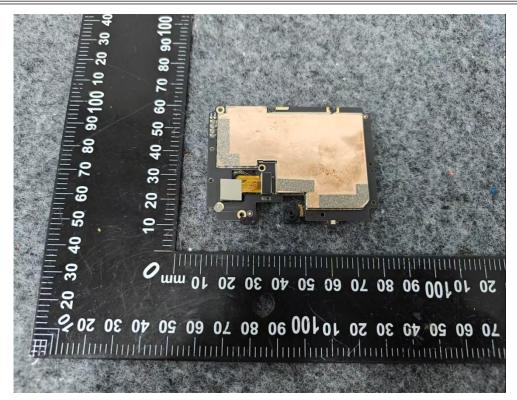


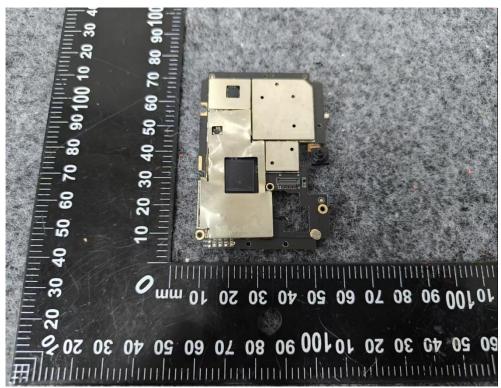




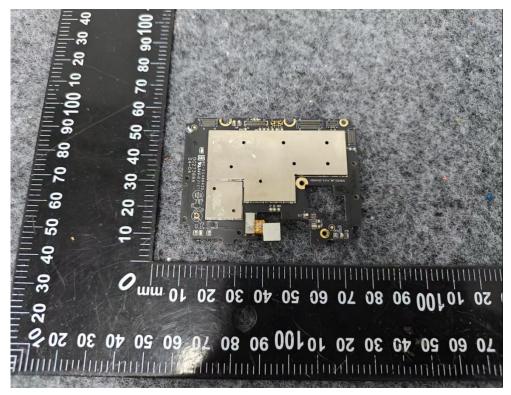


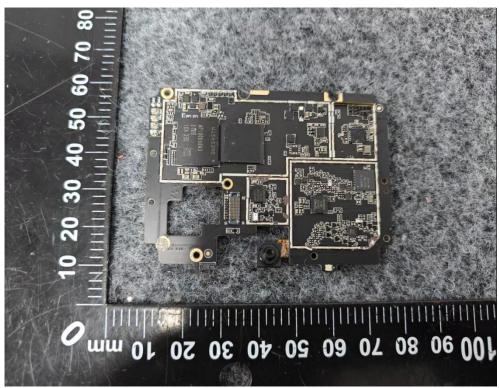




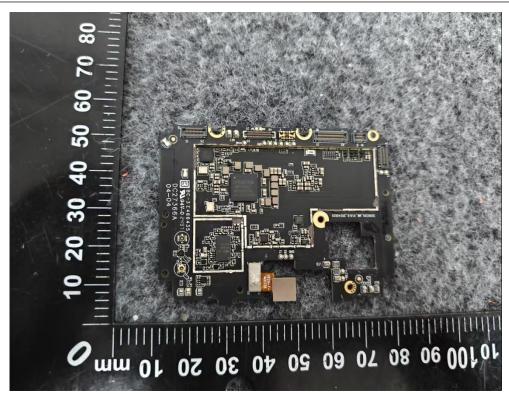


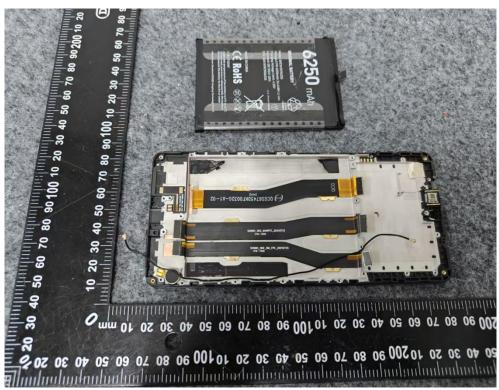
















-----END OF REPORT-----